

Search Notes

Application/Control No.

10/674,278

Examiner

Hanh V. Tran

Applicant(s)/Patent under
Reexamination

DEBRAAL ET AL.

Art Unit

3637

SEARCHED

Class	Subclass	Date	Examiner
108	147 147.19	12/1/2005	HVT
	144.11 150		
108	147.11		
248	188.2		
	188.4		
248	188.5		
5	11 611		
5	614	12/1/2005	HVT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East text search using various key words	12/1/2005	HVT